Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/810,574	LEE, BYUNG-PYLL
Examiner	Art Unit
Hau V. Phan	3618

	SEAR	CHED	
Class	Subclass	Date	Examiner
280	163 164.1 164.2	1/4/2007	HP
	759		
	782		
	830		
239	284.1	1/4/2007	HP
	106		
296	193.12	1/4/2007	HP
15	250.02	1/4/2007	HP
429	100	1/4/2007	HP
220	562	1/4/2007	HP
	890		

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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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